Dimple Vijay Kochar

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Education	Massachusetts Institute of Technology PhD student, Department of Electrical Engineering & Computer Science Advisor: Prof. Anantha Chandrakasan — MIT Energy-Efficient Circuits and Systems GPA: 5.0 / 5.0		
	in terms of general proficiency, excellence i		
Publications	 D. Kochar, H. Wang, X. Zhang, A. Chandrakasan, "LEDRO: LLM-Enhanced Design Space Reduction and Optimization for Analog Circuits," submitted to <i>IEEE Design, Automation and</i> <i>Test in Europe (DATE)</i>, 2025. MIT D. Kochar, M. Ashok, and A. Chandrakasan, "A 0.75mm² 407µW real-time speech audio denoiser with quantized cascaded redundant convolutional encoder-decoder for wearable IoT devices," submitted to <i>International Conference on VLSI Design</i>, 2025. MIT S. Kim, C. Jung, D. Kochar, "Compute-in-Memory with Current Transition Detection," U.S. App. No. 18/403,010, 2024. <i>Qualcomm</i> D. Kochar, T. Samadder, S. Mukhopadhyay and S. Mahapatra, "Modeling of HKMG Stack Process Impact on Gate Leakage, SILC and PBTI," <i>IEEE International Reliability Physics</i> Symposium (<i>IRPS</i>), 2021, pp. 1-7, doi: 10.1109/IRPS46558.2021.9405154. [paper] <i>IITB</i> D. Kochar and A. Kumar, "Estimation of Time to Failure Distribution in SRAM Due to Trapped Oxide Charges," <i>IEEE International Symposium on Circuits and Systems (ISCAS)</i>, 2021, pp. 1-5, doi: 10.1109/ISCAS51556.2021.9401180. [paper] <i>IITB</i> T. Samadder, N. Choudhury, S. Kumar, D. Kochar, N. Parihar and S. Mahapatra, "A Physical Model for Bulk Gate Insulator Trap Generation During Bias-Temperature Stress in Differently Processed p-Channel FETs," in <i>IEEE Transactions on Electron Devices</i>, vol. 68, no. 2, pp. 485-490, Feb. 2021, doi: 10.1109/TED.2020.3045960. [paper] <i>IITB</i> S. Kumar*, T. Samadder*, D. Kochar, and S. Mahapatra, "A Stochastic Simulation Framework for TDDB in MOS Gate Insulator Stacks" presented in <i>International Conference on Simulation of Semiconductor Processes and Devices (SISPAD)</i>, 2022. <i>IITB</i> 		
Research Projects	 Learning (RL) and Bayesian Optimization (E to navigate the large design space. We prop the design space for analog circuit sizing, allo knowledge to design. Our approach eliminate Offers broader generalizability across dive 	25 Department Jan '24 - Present nally relies on human expertise, with Reinforcement 30) often requiring extensive time and numerous steps pose using Large Language Models (LLMs) to narrow powing even individuals without extensive circuit design	

- Delivers an average improvement in FoM of up to 20% in low-complexity and 55% in high-complexity op-amps over best baseline across technology nodes, average speed up of 1.6x
- One of the first to benchmarked across 22 amplifier topologies and four FinFET technology nodes

Low Power Speech Enhancement Chip for IoT Device

MIT Nov '22 - Present

Advisor: Prof. Anantha Chandrakasan, EECS DepartmentNov '22 - PresentIntroduction:Audio denoising is crucial for delivering high-quality sound in applications rangingfrom communication devices to entertainment systems.Machine learning (ML) models exhibitstrong audio processing performance in the frequency domain but require efficient hardware design.This work focuses on enhancing audio quality using convolutional encoder-decoder ML models withlow power consumption while meeting real-time processing constraints.

- Fabricated in TSMC 28nm process, consumes 407μ W or 3.24μ J/frame with process time < 8ms
- Achieves the highest audio quality score (PESQ) of 2.79 across -6 to 9 dB SNR range on CHiME2
- Developed a quantized CNN; hardware quantization scheme reduces memory usage by up to 75%; complementary dataflow scheme reduces the on-chip memory accesses by 5-9x

HKMG Stack Process Impact on Gate Leakage, SILC & PBTI [slides]IIT BombayAdvisor: Prof. Souvik Mahapatra, Electrical Engineering DepartmentDec '18 - Oct '20Introduction:The primary impediment to channel length scaling is gate leakage.PBTI and SILCalso get worse at scaled EOT. Recently, RD and RDD models are used for NBTI interface and bulktrap generation in PMOS. This project aims to model direct tunneling leakage, SILC & PBTI alongwith the traps generated in NMOS withdeeply scaled (down to EOT~7Å) HKMG stacks.

- Quantified impact of IL & HK thickness, channel/IL & IL/HK barriers on gate leakage & SILC
- Extracted bulk trap densities from SILC measurements of differently processed NMOS using a WKB tunneling model & used a Reaction-Diffusion-Drift (RDD) framework to model them
- Modelled the traps generated from PBTI stress using the double interface H/H_2 RD framework
- Analysed impact of gate stack process (pre-clean, IL, IL/HK interface, HK & post-HK nitridation) on gate leakage, SILC and PBTI trap generation (using DCIV) at IL/HK interface

Method for Time To Failure Estimation of SRAM due to RTN [slides]IIT BombayAdvisor: Prof. Animesh Kumar, Electrical Engineering DepartmentDec '18 - Nov '20Introduction:Trapping and detrapping of charges in the oxide interface of a MOSFET leads to arandom telegraphic noise (RTN) injection & this phenomenon negatively affects the reliability ofcircuits. The objective of this project is to develop a reproducible strategy to obtain time to failure(TTF) distribution & related statistics for SRAM of any technology with any given RTN model.

- Proposed a method to estimate TTF distribution of a stored bit in an SRAM cell due to single or multi-level RTN by composition of Monte-Carlo simulations & circuit-level abstraction
- Showcased results of this procedure on an SRAM cell with a single-trap RTN model
- Indicated via circuit-level simulations that the TTF distribution worsens due to process variations

Model for Time Dependent Dielectric Breakdown for Thin Oxides[slides]IIT BombayAdvisor: Prof. Souvik Mahapatra, Electrical Engineering DepartmentMay '18 - Jun '21Introduction:Time-dependent dielectric breakdown (TDDB) is characterized by its Weibull slope.In this project, the change in the slope is explained by a percolation model with different defectgeneration rates in the bulk & channel/oxide and gate/oxide interfaces, also considering SILC slopechanges with thickness & trap size. The model is then extended for high-k with interfacial SiO2.

- Designed a cell based oxide percolation model which stochastically creates bulk & interface traps
- Procured time to failure distribution & analysed the relation of its Weibull slope with oxide thickness & obtained results obeying experimental data varying with voltage & temperature
- Proposed and demonstrated a hypothesis for differences in bulk trap & SILC slopes

Research	Making In-Memory Computing Reliable	Qualcomm
INTERNSHIPS	Memory IP Team, San Diego	Jun '23 - Aug '23
	Introduction: A major percentage of today's deep learning architecture are the MAC operations. If	
	the weights are stored in the foundry 8-T bit-cell, and the RWL has the in	nput coming in, current
	proportional to the compute output passes through the RBL. Due to process variations, this current	
	varies in a large range. Foundry bit-cell is essential to use SRAM design rule	s and ensure scalability.

- To solve this problem, two approaches were implemented in TSMC N3E technology node.
- Filed a patent app. for a robust against process variations technique for accurate IMC SRAM
- $\bullet\,$ Developed a circuit + ML model for bit prediction with 96.4% accuracy in TSMC N3E 8T SRAM

Dipole-Exchange Spin Waves in Thin Ferromagnetic Films slides

Advisors: Prof. Gerrit Bauer, Kavli Institute of Nanoscience

Prof. Yaroslav Blanter, Kavli Institute of Nanoscience

Introduction: Dispersion characteristics of spin waves in ferromagnetic films taking into account both the dipole-dipole and the exchange interactions are obtained by a sixth-order differential equation. The objective of this project is to solve it considering pinned and unpinned boundary conditions & study their variation with thickness in this transition region.

- Calculated the wave function, magnetization & dipolar field profiles for various modes of spin waves by solving Landau–Lifshitz & Maxwells' equations & appropriate boundary conditions
- Showed how chirality changes with thickness; obtained the dispersion relation (ω vs \vec{k}) for a film
- Obtained isofrequency curves & showed their change with increase in magnetic field in \vec{k} space

• Conferred the 'Grass Instrument Company Fellowship' to support first year at MIT ACHIEVEMENTS

- Bestowed the 'Desai-Sethi Scholarship' awarded to the top 5 girls admitted to IIT Bombay
- Achieved All India Rank 102 in JEE Main and All India Rank 295 in JEE Advanced out of 1.2 & 0.2 million candidates respectively; stood first in both in the state of Maharashtra among girls
- Awarded the 'Travel Grants for UG students by C'1992 and C'1998' for IEEE ISCAS 2021

Ring Oscillator Characterization TECHNICAL Projects

Scholastic

• Taped out in 14nm Samsung technology, designed for accurate power & frequency measurements

Low Power FC-CS CMOS Operational Amplifier

• Designed an FC-CS CMOS opamp in 22nm bsim4 with power < 1.5mW, settling times < 8ns, open loop gain > 10k, thermal noise < 300uV, phase margin > 65° at gain-of-2 frequency

Power Amplifier Design for function at 520 MHz

- Constructed matching networks using microstrip transmission lines and fabricated it on FR4 substrate to obtain a gain of 2.5 dB at 520 MHz with S_{11} and S_{12} values -18 dB and -35 dB
- Sub-100nm Gate GaN HEMT transistor fabrication Device Fabrication • Fabricated a HEMT on GaN-on-Si with an $I_{ON} = 1.3$ A/mm and $R_{ON} = 1.54\Omega$ at MIT.nano
- Broadband 4×4 Butler Matrix Circuit at 5.4GHz Microwave Integrated Circuits
- Constructed 90° hybrids & phase delay lines using microstrip transmission lines to equally divide power, fabricated on FR4 substrate & achieved equal power division and input port isolation

Other projects:

- Implemented IITB-RISC on DE0-Nano FPGA, an 8-register, 16-bit system with 15 instructions in standard 6 stage pipelines & equipped it with control flow, data forwarding & hazard mitigation
- Awarded the best among 70+ projects for implementing an audio volume controller, motion tracker & a pattern lock by gesture detection using infrared emitters & sensors and CPLD
- Stood in the top 5 teams in the Make in India presentation organised for TEQIP-III for heart rate variability analysis by processing the ECG signal & PSD to predict risk of myocardial infarction

Teaching &	Teaching Assistant for MIT Course		
Mentoring	6.6000 (6.775): CMOS Analog and Circuit Design, Spring '24		
Experience	Teaching Assistant for IIT Bombay Courses		
	EE302: Control Systems, Spring '21	EE325: Probability & Random Processes, Fall '20	
	MA108: Differential Equations, Spring '18 $$	PH107: Quantum Mechanics, Fall '17	
	Mentor, Graduate Application Assistance Program, EECS, MIT 2023 Mentor, Department Academic Mentorship Program, IIT Bombay 2019-2021		
Editor, Insight, IIT Bombay	Apr '18 - Mar '19		
Official Print Media Body Circulated to 10K+ students & 650+ faculty Online readership 0.4M+			
Convenor, IIT Bombay Broadcasting Char	anel Apr '17 - Mar '18		
$Official \ Multimedia \ Journalism \ Body \mid 50K+ \ YouTube \ Subscribers \mid 25K+ \ Facebook \ Followers$			

$TU \ Delft$ May '19 - Jul '19

Analog Circuits

Solid State Microwave Devices

MIT-IBM AI Watson Lab